S	earcn	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/708,371	CHAN ET AL.	
Examiner	Art Unit	
Linh V. Nguyen	2819	

	SEAR	CHED	
Class	Subclass	Date	Examiner
330	285,261 196	6/9/2005	LN
			;

INT	ERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
330	136	6/9/2005	LN

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
high, power, amplifier, bias, input ,gate, diode, resistior	6/9/2005	LN
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